www.DataSheet4110SHIBA INSULATED GATE BIPOLAR TRANSISTOR SILICON N CHANNEL IGBT

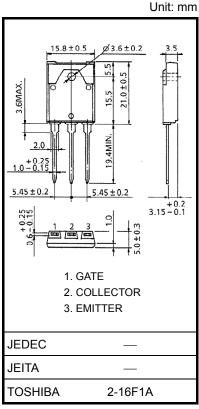
# GT35J321

# Fourth-generation IGBT Current Resonance Inverter Switching Applications

- Enhancement mode
- High speed:  $t_f = 0.19 \, \mu s$  (typ.) (I<sub>C</sub> = 50 A)
- Low saturation voltage:  $V_{CE}$  (sat) = 1.9 V (typ.) (IC = 50 A)
- FRD included between emitter and collector
- Toshiba package name: TO-3P(N)IS

## **Absolute Maximum Ratings (Ta = 25°C)**

Characteristics		Symbol	Rating	Unit	
Collector-emitter voltage		V <sub>CES</sub>	600	V	
Gate-emitter voltage		$V_{GES}$	±25	٧	
Collector current (DC)	@ Tc = 100°C	la	18	А	
	@ Tc = 25°C	IC	37		
Collector current (pulse)		I <sub>CP</sub>	100	Α	
Diode forward current	DC	lF	20	Α	
	Pulse	I <sub>FP</sub>	40		
Collector power dissipation	@ Tc = 100°C	Pc	30	W	
	@ Tc = 25°C	FC	75		
Junction temperature		Tj	150	°C	
Storage temperature range		T <sub>stg</sub>	-55 to 150	°C	



Weight: 5.8 g (typ.)

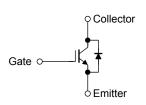
Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

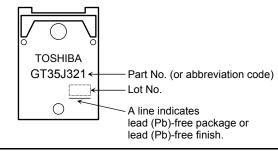
#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance (IGBT)	R <sub>th (j-c)</sub>	1.67	°C/W
Thermal resistance (diode)	R <sub>th (j-c)</sub>	3.2	°C/W

#### **Equivalent Circuit**



### Marking

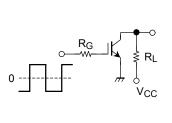


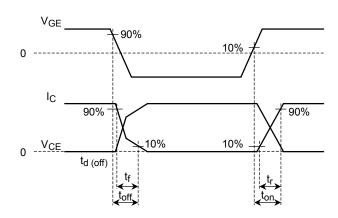


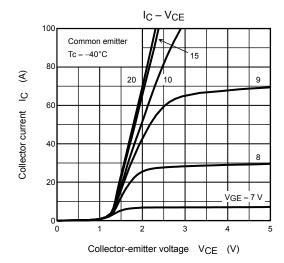
#### www.DataSheet4U com Electrical Characteristics (Ta = 25°C)

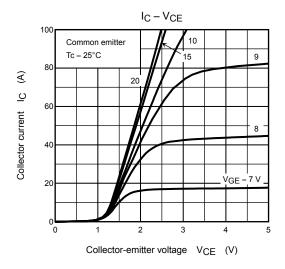
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit	
Gate leakage current		I <sub>GES</sub>	V <sub>GE</sub> = ±25 V, V <sub>CE</sub> = 0 V	_	_	±500	nA	
Collector cut-off current		I <sub>CES</sub>	V <sub>CE</sub> = 600 V, V <sub>GE</sub> = 0 V	_	_	1.0	mA	
Gate-emitter cut-off voltage		V <sub>GE</sub> (OFF)	I <sub>C</sub> = 50 mA, V <sub>CE</sub> = 5 V	3.0	_	6.0	V	
Collector-emitter saturation voltage		V <sub>CE</sub> (sat)	I <sub>C</sub> = 50 A, V <sub>GE</sub> = 15 V	_	1.9	2.3	V	
Input capacitance		C <sub>ies</sub>	V <sub>CE</sub> = 10 V, V <sub>GE</sub> = 0 V, f = 1 MHz	_	2500	_	pF	
Switching time	Rise time	t <sub>r</sub>	Resistive Load	_	0.24	_	μs	
	Turn-on time	t <sub>on</sub>	V <sub>CC</sub> = 300 V, I <sub>C</sub> = 50 A	_	0.33	_		
	Fall time	t <sub>f</sub>	$V_{GG}$ = ±15 V, $R_{G}$ = 39 $\Omega$	_	0.19	0.32		
	Turn-off time	t <sub>off</sub>	(Note 1)	_	0.51	_		
Diode forward voltage		V <sub>F</sub>	I <sub>F</sub> = 15 A, V <sub>GE</sub> = 0 V	_	_	2.0	V	
Reverse recovery time		t <sub>rr</sub>	I <sub>F</sub> = 15 A, di / dt = -100 A / μs	_	_	0.2	μs	

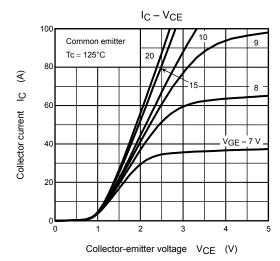
Note 1: Switching time measurement circuit and input/output waveforms

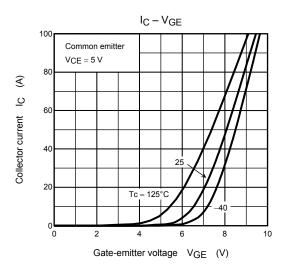


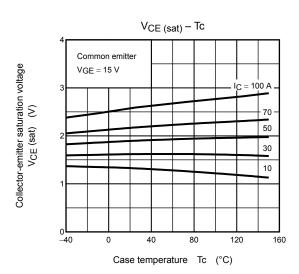


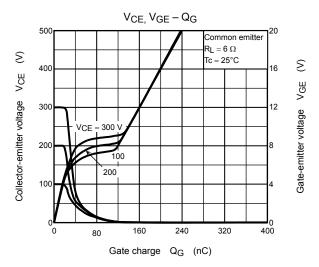


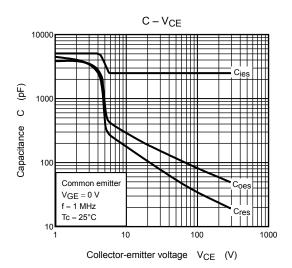


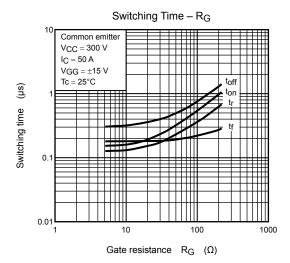


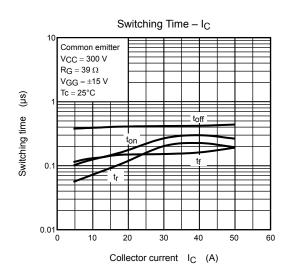


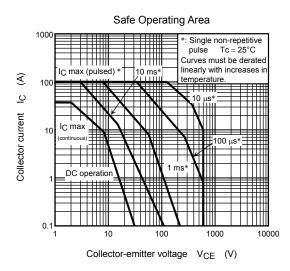


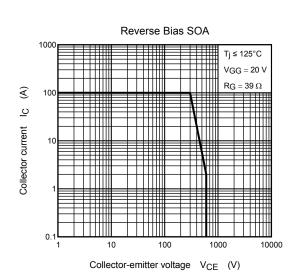


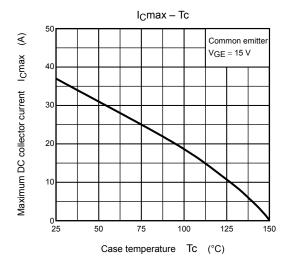


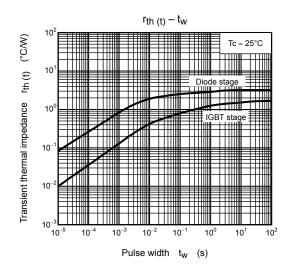


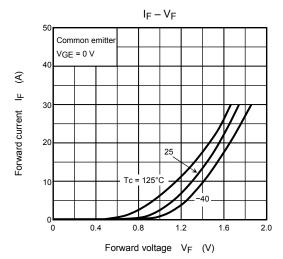


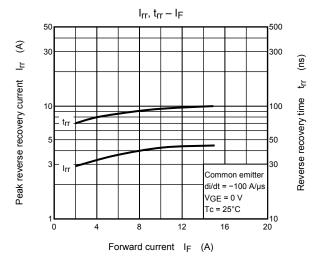


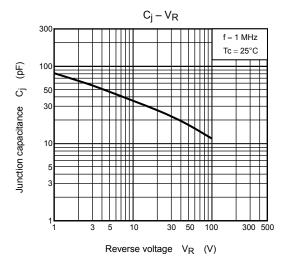


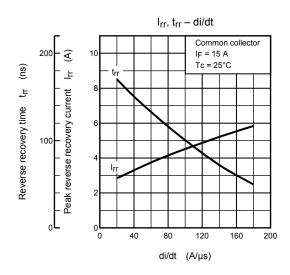












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